

IRFH7923PbF

Applications

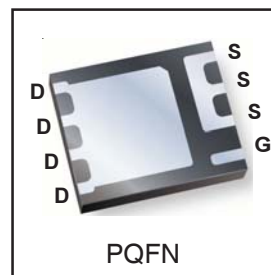
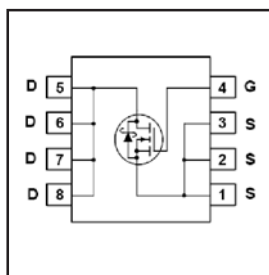
- High Frequency Point-of-Load Synchronous Buck Converter for Applications in Networking & Computing Systems
- Optimized for Control FET Applications

HEXFET® Power MOSFET

V_{DSS}	$R_{DS(on)}$ max	Qg
30V	$8.7m\Omega @ V_{GS} = 10V$	8.7nC

Benefits

- Very low $R_{DS(ON)}$ at 4.5V V_{GS}
- Low Gate Charge
- Fully Characterized Avalanche Voltage and Current
- 100% Tested for R_G
- Lead-Free (Qualified up to 260°C Reflow)
- RoHS compliant (Halogen Free)
- Low Thermal Resistance
- Large Source Lead for more reliable Soldering



Absolute Maximum Ratings

	Parameter	Max.	Units
V_{DS}	Drain-to-Source Voltage	30	V
V_{GS}	Gate-to-Source Voltage	± 20	
$I_D @ T_A = 25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$	15	A
$I_D @ T_A = 70^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$	12	
$I_D @ T_C = 25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$	33	
I_{DM}	Pulsed Drain Current ①	120	
$P_D @ T_A = 25^\circ C$	Power Dissipation ②	3.0	W
$P_D @ T_A = 70^\circ C$	Power Dissipation ②	1.9	
	Linear Derating Factor ③	0.02	W/°C
T_J	Operating Junction and	-55 to + 150	°C
T_{STG}	Storage Temperature Range		

Thermal Resistance

	Parameter	Typ.	Max.	Units
$R_{\theta JC}$	Junction-to-Case ④	—	8.3	°C/W
$R_{\theta JA}$	Junction-to-Ambient ⑤	—	42	

Notes ① through ⑤ are on page 9

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IR RectifierStatic @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

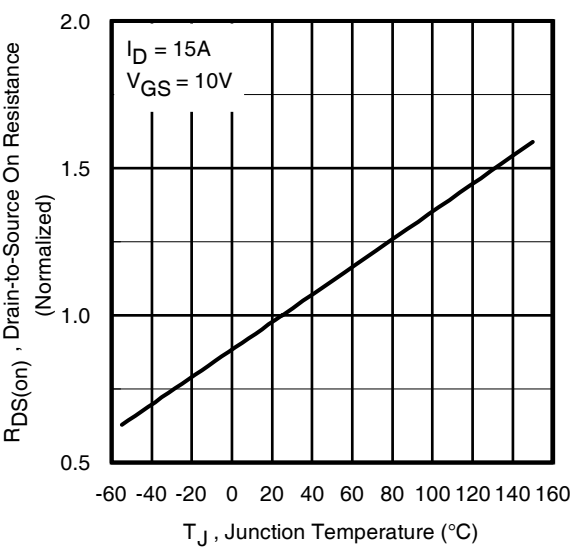
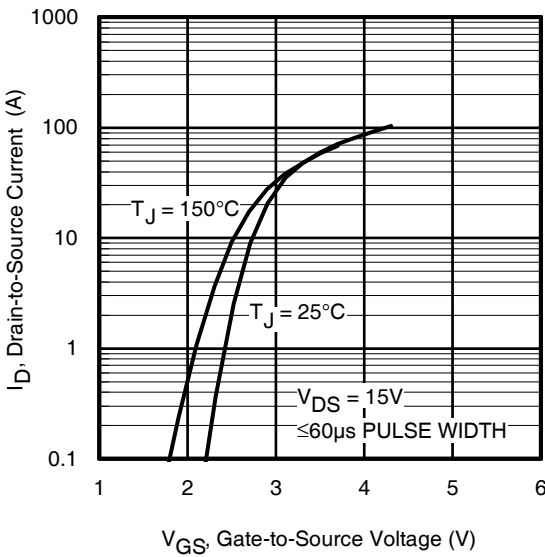
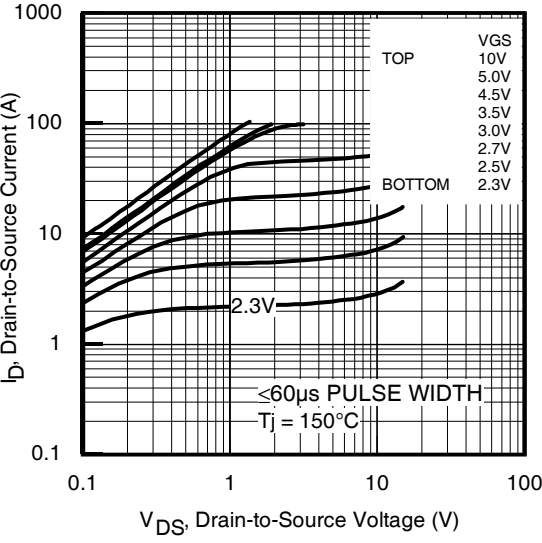
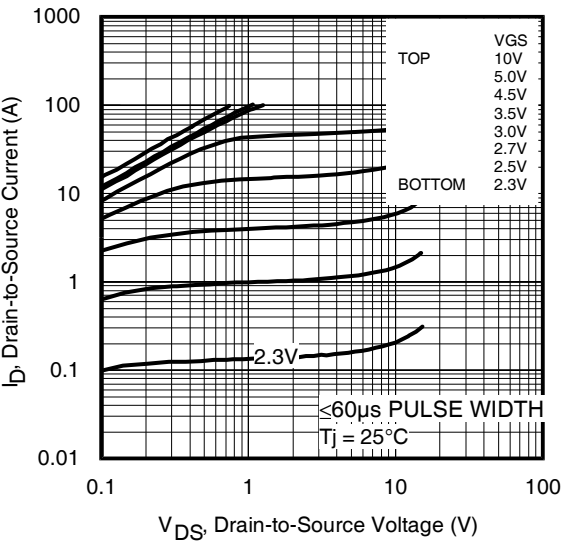
	Parameter	Min.	Typ.	Max.	Units	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	30	—	—	V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta BV_{DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient	—	0.024	—	V/ $^\circ\text{C}$	Reference to $25^\circ\text{C}, I_D = 1mA$
$R_{DS(on)}$	Static Drain-to-Source On-Resistance	—	6.8	8.7	$m\Omega$	$V_{GS} = 10V, I_D = 15A$ ③
		—	9.3	11.9		$V_{GS} = 4.5V, I_D = 12A$ ③
$V_{GS(th)}$	Gate Threshold Voltage	1.35	1.8	2.35	V	$V_{DS} = V_{GS}, I_D = 25\mu A$
$\Delta V_{GS(th)}$	Gate Threshold Voltage Coefficient	—	-5.8	—	mV/ $^\circ\text{C}$	
I_{DSS}	Drain-to-Source Leakage Current	—	—	1.0	μA	$V_{DS} = 24V, V_{GS} = 0V$
		—	—	150		$V_{DS} = 24V, V_{GS} = 0V, T_J = 125^\circ\text{C}$
I_{GSS}	Gate-to-Source Forward Leakage	—	—	100	nA	$V_{GS} = 20V$
	Gate-to-Source Reverse Leakage	—	—	-100		$V_{GS} = -20V$
g_{fs}	Forward Transconductance	29	—	—	S	$V_{DS} = 15V, I_D = 12A$
Q_g	Total Gate Charge	—	8.7	13	nC	$V_{DS} = 15V$ $V_{GS} = 4.5V$ $I_D = 12A$ See Fig.17 & 18
Q_{gs1}	Pre-V _{th} Gate-to-Source Charge	—	1.8	—		
Q_{gs2}	Post-V _{th} Gate-to-Source Charge	—	1.1	—		
Q_{gd}	Gate-to-Drain Charge	—	2.7	—		
Q_{godr}	Gate Charge Overdrive	—	3.1	—		
Q_{sw}	Switch Charge ($Q_{gs2} + Q_{gd}$)	—	3.8	—		
Q_{oss}	Output Charge	—	4.9	—	nC	$V_{DS} = 16V, V_{GS} = 0V$
R_G	Gate Resistance	—	2.0	3.0	Ω	
$t_{d(on)}$	Turn-On Delay Time	—	7.1	—	ns	$V_{DD} = 15V, V_{GS} = 4.5V$ $I_D = 12A$ $R_G = 1.8\Omega$ See Fig.15
t_r	Rise Time	—	8.7	—		
$t_{d(off)}$	Turn-Off Delay Time	—	8.6	—		
t_f	Fall Time	—	4.9	—		
C_{iss}	Input Capacitance	—	1095	—	pF	$V_{GS} = 0V$ $V_{DS} = 15V$ $f = 1.0MHz$
C_{oss}	Output Capacitance	—	235	—		
C_{rss}	Reverse Transfer Capacitance	—	110	—		

Avalanche Characteristics

	Parameter	Typ.	Max.	Units
E_{AS}	Single Pulse Avalanche Energy ②	—	26	mJ
I_{AR}	Avalanche Current ①	—	12	A

Diode Characteristics

	Parameter	Min.	Typ.	Max.	Units	Conditions
I_S	Continuous Source Current (Body Diode)	—	—	3.7	A	MOSFET symbol showing the integral reverse p-n junction diode.
I_{SM}	Pulsed Source Current (Body Diode) ①	—	—	120		
V_{SD}	Diode Forward Voltage	—	—	1.0	V	$T_J = 25^\circ\text{C}, I_S = 12A, V_{GS} = 0V$ ③
t_{rr}	Reverse Recovery Time	—	12	18	ns	$T_J = 25^\circ\text{C}, I_F = 12A, V_{DD} = 15V$
Q_{rr}	Reverse Recovery Charge	—	11	17	nC	$di/dt = 300A/\mu s$ ③
t_{on}	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD)				



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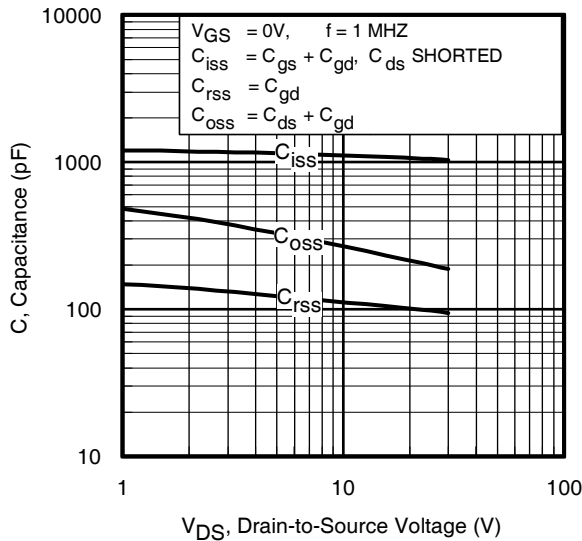


Fig 5. Typical Capacitance Vs. Drain-to-Source Voltage

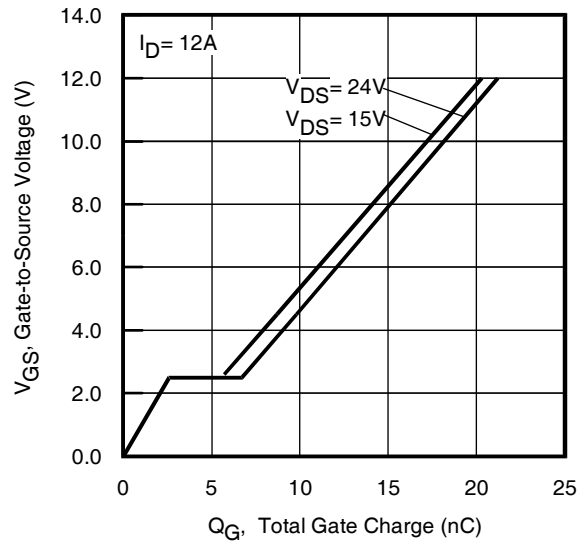


Fig 6. Typical Gate Charge Vs. Gate-to-Source Voltage

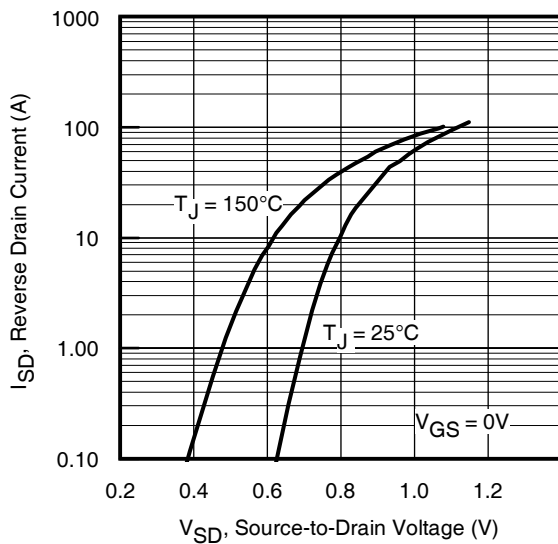


Fig 7. Typical Source-Drain Diode Forward Voltage

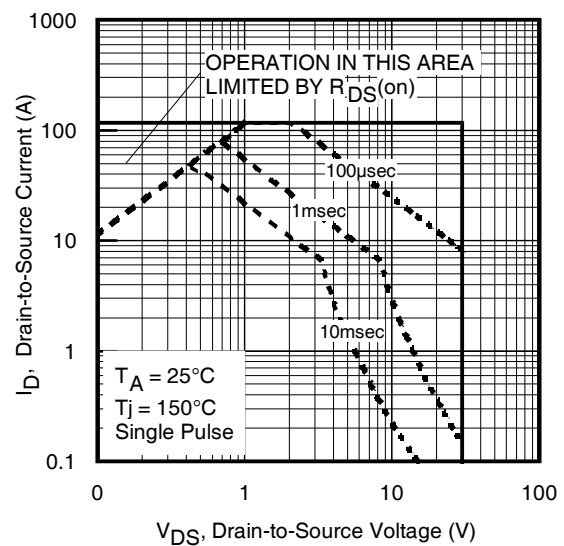


Fig 8. Maximum Safe Operating Area

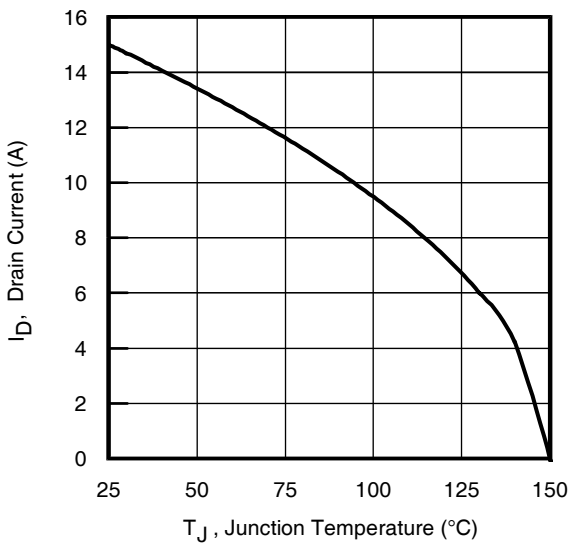


Fig 9. Maximum Drain Current Vs. Ambient Temperature

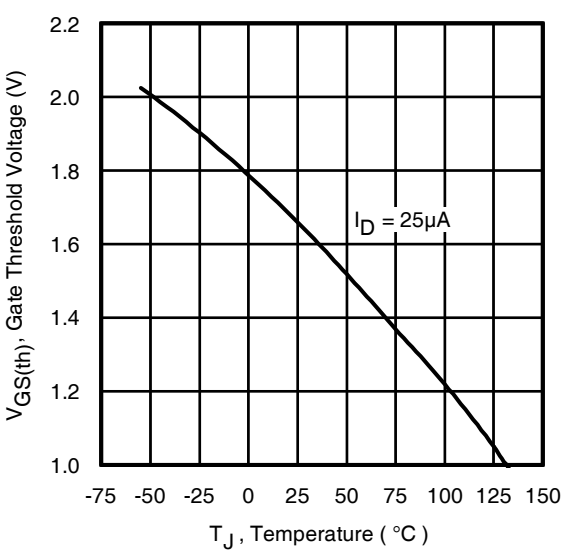


Fig 10. Threshold Voltage Vs. Temperature

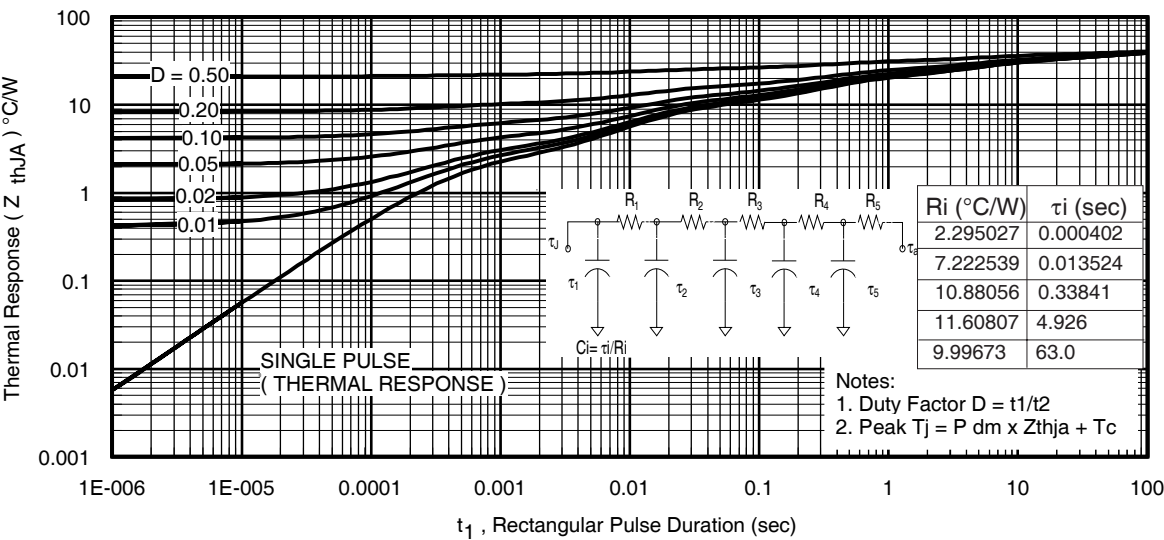


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Ambient

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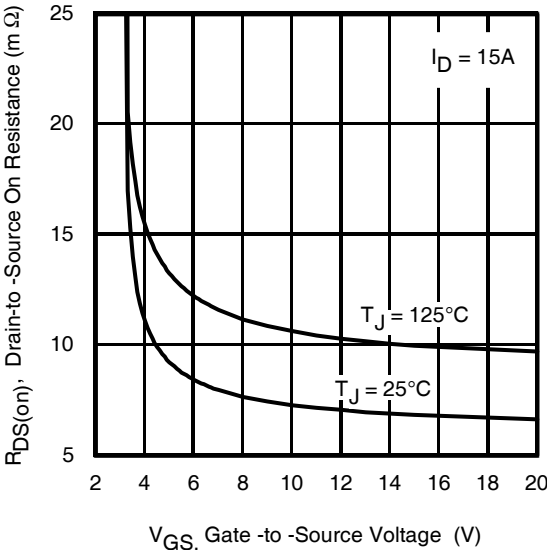


Fig 12. On-Resistance vs. Gate Voltage

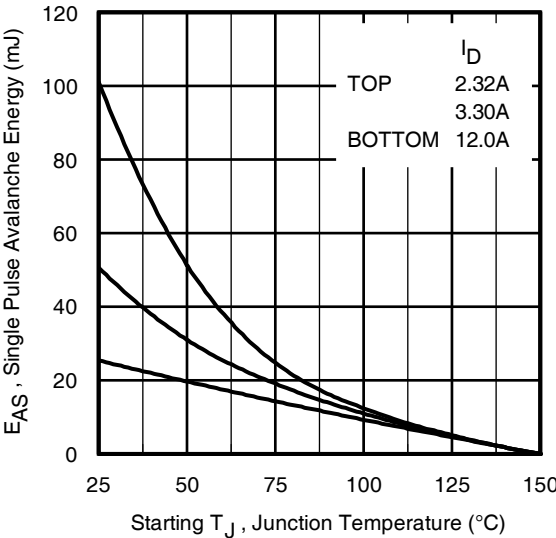


Fig 13. Maximum Avalanche Energy vs. Drain Current

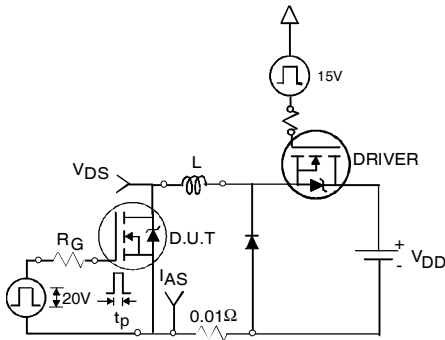


Fig 14a. Unclamped Inductive Test Circuit

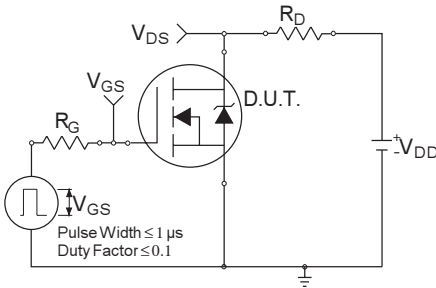


Fig 15a. Switching Time Test Circuit

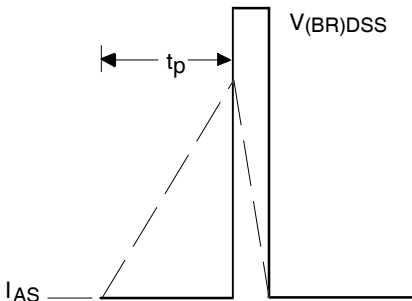


Fig 14b. Unclamped Inductive Waveforms

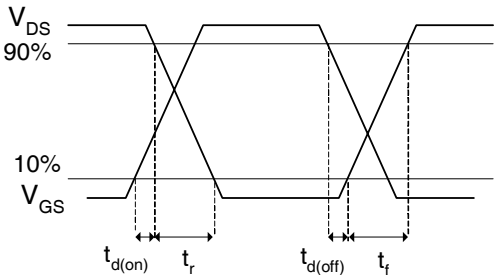


Fig 15b. Switching Time Waveforms

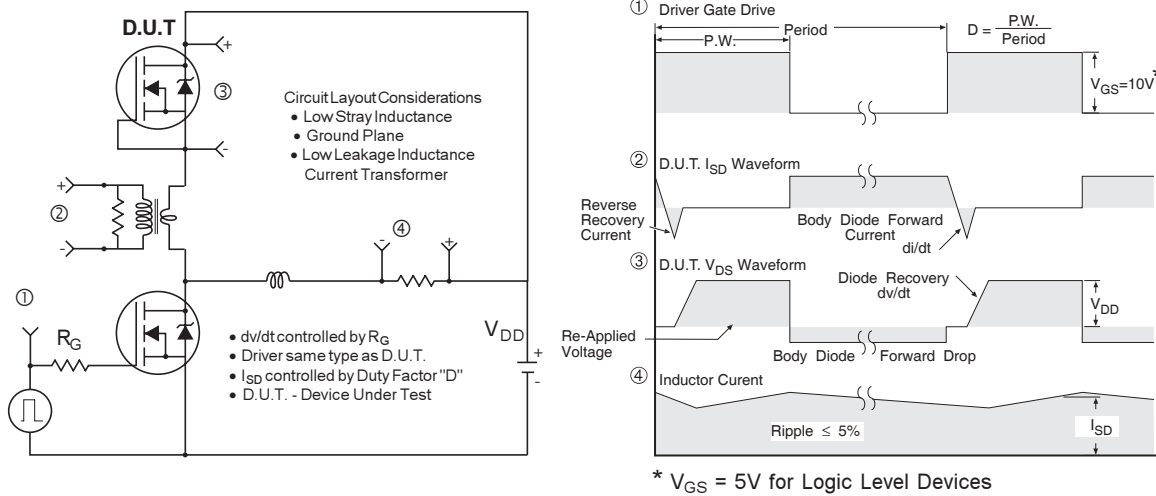


Fig 16. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

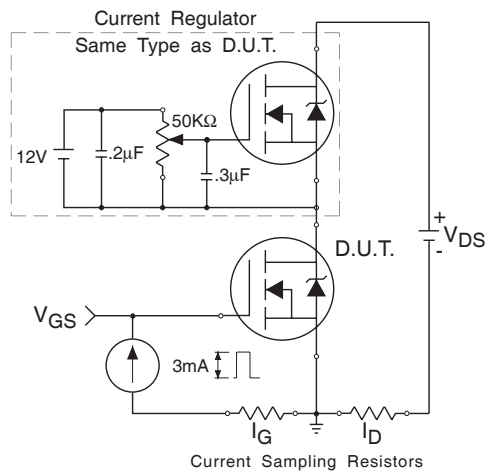


Fig 17. Gate Charge Test Circuit

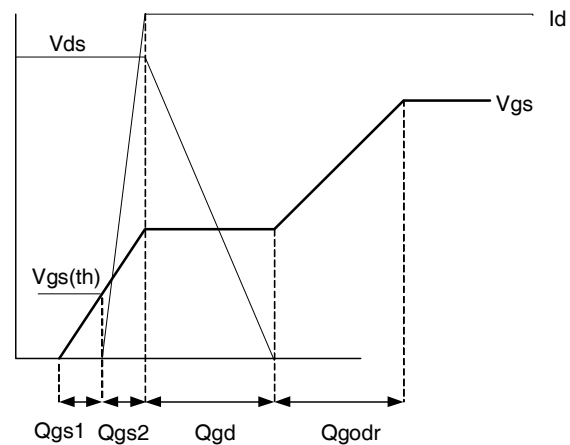
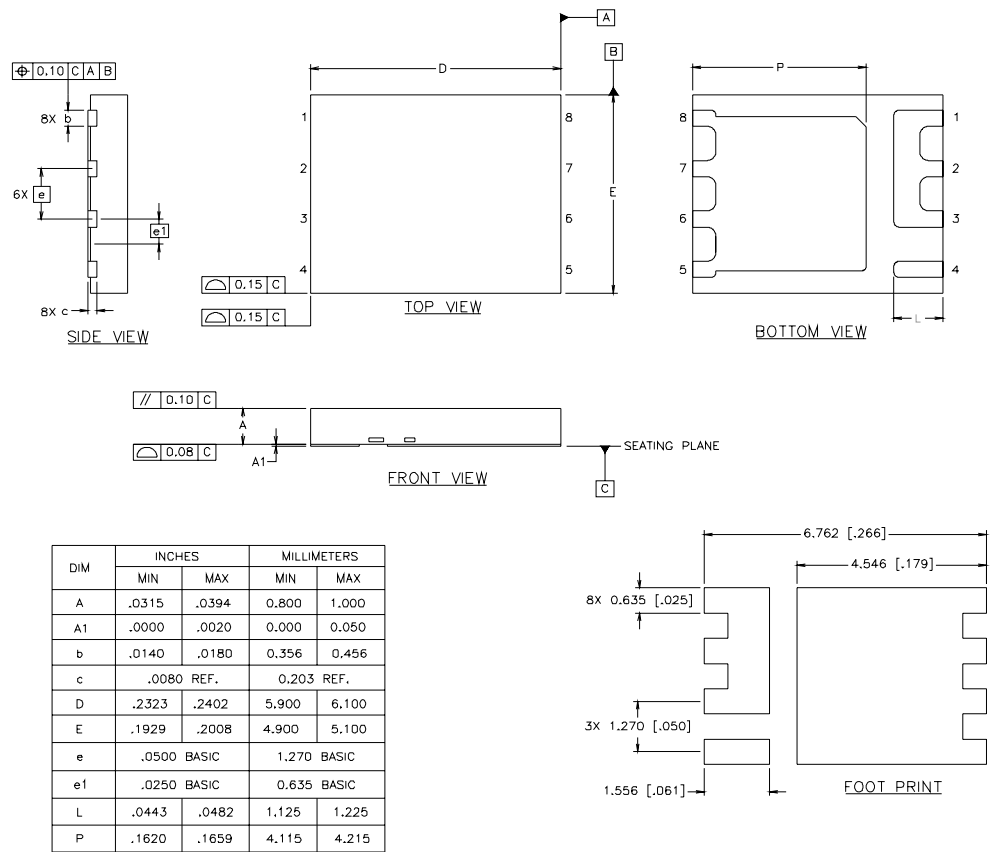


Fig 18. Gate Charge Waveform

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PQFN Package Details



PQFN Part Marking

